



Global Cavity Data Base & Gradient Yield

Rongli Geng
Jefferson Lab



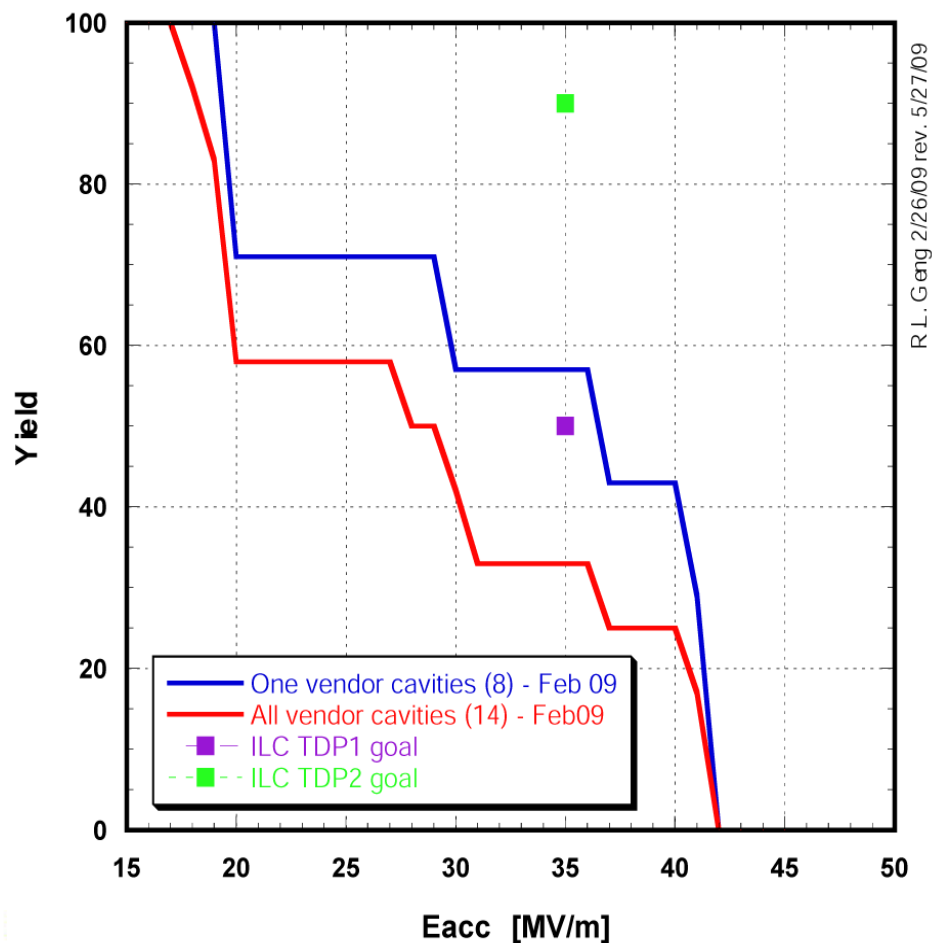
Two-Pass Yield Proposal @ AD&I Mtg

First-pass result decides path forward:

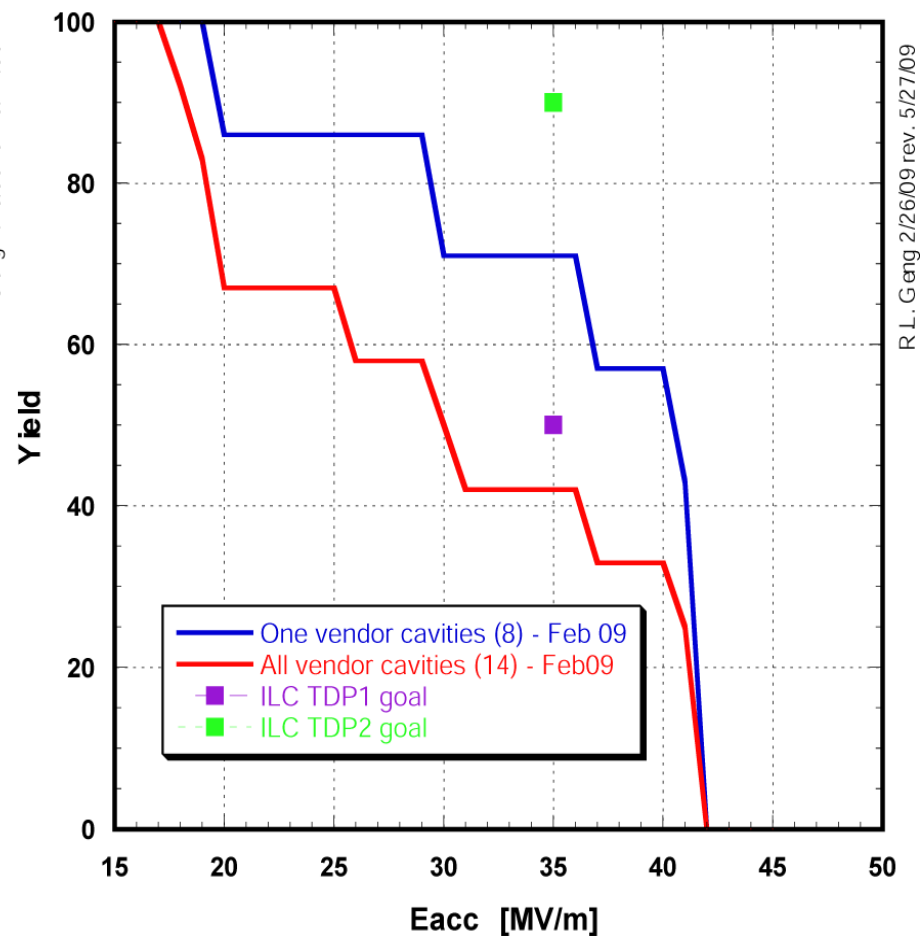
- Move on for S1 if spec met
- Re-process (Re-HPR; Re-EP; Local repair) if spec not met

An example based on real data from JLab

First Pass Gradient Yield as of Feb 09



Gradient Yield up to 2 pass - as of Feb 09



Global Data Collection

- Q: which cavity should be included?
 - **cavities made/processed w/ “standard recipe”**
 - **Truth is there is no uniform specification for cavity fabrication or processing**
 - Finished EBW spec?
 - EP process spec?
 - End surface spec?
 - **Obvious variability examples**
 - Material from different vendors
 - Cavity shape difference
 - EBW weld prep & orientation
 - Pre-EP surface treatment
 - EP parameters and protocols, EP orientation
 - Hydrogen out-gassing time and temperature





Global Data Collection

- Proposition 1: all cavities fabricated and processed according to following rough steps
 - **Fine grain sheet material**
 - **Deep drawing & EBW**
 - **Initial field flatness tuning**
 - **Bulk EP for heavy removal**
 - **H2 removal with vacuum furnace**
 - **Final tuning field flatness (and frequency)**
 - **Final EP for light removal**
 - **Post-EP cleaning**
 - **Clean room assembly**
 - **Low temperature bake-out**
 - **2K RF test**



Global Data Collection

- Proposition 2: accept known variabilities
 - **Fine grain niobium irrespective of vendors**
 - **EBW irrespective of prep design welding para.**
 - **Cavities w/ or without helium tank**
 - **With or without pre-EP treatment (BCP, CBP...)**
 - **EP irrespective of parameters & protocols**
 - Horizontal EP or vertical EP
 - H₂SO₄/HF/H₂O ratio, pre-mixing or on-site mixing
 - Cell temp. control or return acid temp. control
 - W/ or w/o acid circulation after voltage shut off
 - Post-EP cleaning: ER or USC or H₂O₂ rinsing
 - **H₂ out-gassing irrespective of temp. & time**
 - **HPR irrespective of nozzle style, HPR time**
 - **CR assembly irrespective of practice variability**



First-Pass Data

- What it is
 - **First RF test result following all steps applied**
 - **Should be the final power rise data**
 - as some cavities “processing” well
- What it is not
 - **May not necessarily the first RF test of the cavity**
 - Example: some cavities were tested before low temperature bake-out for FE screening purpose
 - **Should not include data of cavities with known material flaw, equipment malfunctioning, human error etc.**



Second-Pass Data

- What it is
 - **Cavities failed to meet ILC gradient and Q spec**
 - **Re-treated and re-tested for a second time; re-treatment can be:**
 - Re-HPR (for FE reduction)
 - Re-EP (for FE reduction or defect removal)
 - Post-purification (for defect stabilization) ?
 - Repair (local grinding, local re-melting...) followed by re-process and re-test (for defect removal)
- What it is not
 - **Cavities already passing ILC spec**
 - **Re-test without physical changes on RF surface (e.g. T-mapping test)**



Beyond Two Pass...

- Some cavities may be re-processed and re-tested more than two passes anyway for various reasons
- We may still want to monitor these data for purpose of learning.
- Cavity exchange effort falls into this category
 - **For cross checking facilities**
 - **For cross checking processing variability**
 - **For cross-calibrating measurement error bars**



Challenges and Opportunities

- Challenge: Integrating globally data with known variability in cavity fab., proc. & handling
- It is possible yield of sub-set data may be different
 - **materials from different vendors**
 - **cavities manufactured by different vendors**
 - **cavities processed at different labs**
- Provides reality of “global” gradient
- True leaning opportunities toward “standard recipe”
- This global data base effort will be very useful and success is necessary
- Thank Camille for her leadership & excellent start



Comments

- Should include cavities even with known defect – but should be flagged not for gradient yield evaluation